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# RELIABILITY GROWTH DURING A DEVELOPMENT TESTING PROGRAM

Richard E. Barlow and Ernest M. Scheuer

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# RELIABILITY GROWTH DURING A DEVELOPMENT TESTING PROGRAM

Richard E. Barlow and Ernest M. Scheuer

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# PREFACE

During its development testing, a system may undergo modification to remedy design weaknesses which the tests reveal. The changes are made to improve the reliability of the system, and if such improvement occurs, we say that <u>reliability growth</u> is taking place.

This RAND Memorandum derives statistical methods for estimating reliability under growth assumptions which merely require that changes made to the system which is being tested do not make it worse. The methods differ from previous methods, which either ignore growth or assume that growth is taking place in an assigned functional manner.

While this Memorandum is addressed primarily to statisticians, it should also be of interest to test engineers and managers concerned with assessing a system's reliability. The investigation was undertaken as a part of the Apollo Contingency Planning Study which RAND is conducting for Headquarters, NASA, under Contract NAST-21(09). One of the authors, Richard E. Barlow, is a consultant to The RAND Corporation.

#### SUMMARY

This study examines the problem of estimating the reliability of a system that is undergoing development testing. In such a program, changes are made to the system from time to time in order to increase its reliability. This study assumes that these changes are at least not deleterious, and, unlike some previous work in this area, it does not assume that system modifications cause reliability growth according to a prescribed functional form. The method described herein does, however, require that each failure be classified as inherent or reflecting a correctable cause.

The study proceeds on the supposition that the test program is conducted in K stages, with similar items being tested within each stage. For each stage, the number of inherent failures, of assignable cause failures, and of successes is recorded. It is supposed that the probability of an inherent failure,  $\mathbf{q}_0$ , remains the same throughout the test program and that the probability of an assignable cause failure in the i-th stage,  $\mathbf{q}_i$ , does not increase from stage to stage of testing. This Memorandum obtains maximum likelihood estimates of  $\mathbf{q}_0$  and of the  $\mathbf{q}_i$ 's subject to the condition that they be non-increasing, and also obtains a conservative lower confidence interval for  $\mathbf{r}_K$ , the reliability of the system in its final configuration of the test program. Numerical examples to illustrate these methods are given.

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### I. INTRODUCTION

It is common practice, during the development of a system, to make engineering changes as the program develops. These changes are generally made in order to correct design deficiencies and, thereby, to increase reliability. This elimination of design weaknesses is what we mean by reliability growth.

The concept of reliability growth has been discussed by several authors. We mention some studies with which we are familiar.

Lloyd and Lipow in Chapter 11 of their book [1] give a model in which a system has only one failure mode; if the system operates successfully at a trial, no redesign action is taken prior to the next trial. If it fails at a trial, the designers attempt a modification which has a given probability of being successful. This model leads to an exponential growth model of the form.

(1) 
$$R_n = 1 - A e^{-C(n-1)}$$
,

in which R is the reliability of the system at the n-th trial and A and C are parameters to be estimated. Lloyd and Lipow also consider a situation in which a test program is conducted in N stages, each stage consisting of a certain number of trials of the item under test. All tests in a given stage of testing involve similar items. The results of each stage of testing are used to improve the item for further testing in the next stage. They impose on the data a reliability growth function of the form

$$R_{k} = R_{\infty} - \alpha/k ,$$

where  $R_k$  is the reliability during the k-th stage of testing, and  $R_\infty$  (the "ultimate" reliability) and  $\alpha$  are parameters. Lloyd and Lipow give maximum likelihood and least squares estimates of  $R_\infty$  and  $\alpha$  and a lower confidence limit for  $R_k$ . Finally, they suggest some other forms that reliability growth models might take.

Wolman [2] considers a model in which a distinction is made between inherent (random) failures and assignable cause failures. He supposes that the number of design weaknesses (the source of assignable cause failures) is known and that they all have the same probability of causing a failure on a particular trial. Further, once a design weakness is observed, it is eliminated and will never again cause a system failure. Wolman is interested in calculating quantities such as the probability of eliminating all design weaknesses in n trials (assuming as known the probabilities of the two kinds of failure) -- not in estimating the parameters of his model. That is, his is a probabilistic model. (A statistical model is discussed below.)

Madansky and Peisakoff [3] have examined some data from Thor and Atlas Missile flights. They, too, distinguished between inherent and assignable cause failures and batched together data from comparable test units, but made no explicit use of any statistical model.

H. K. Weiss [4] has considered reliability growth as a process by which the mean time to failure of a system with exponential failure distribution is increased by removing failure causes during a development program.

Two related papers which have appeared recently are by Bresenham [5] and Corcoran, Weingarten, and Zehna [6].

### II. A TRINOMIAL MODEL FOR RELIABILITY GROWTH

We propose the following model for a development program experiencing reliability growth. The test program is conducted in K stages. At each stage of experimentation, tests are run on similar items. results of each stage of testing are used to improve the item for further testing in the next stage. We record for the i-th stage the number, a, of inherent failures, the number, b, of assignable cause failures,  $^{**}$  and the number,  $c_i$ , of successes. The probability of an inherent failure,  $q_0$ , is assumed to be constant and not to change from stage to stage of testing. The probability of an assignable cause failure in the i-th stage is  $\mathbf{q}_{\mathbf{i}}$ . Each trial results in exactly one of the outcomes: success, inherent failure, or assignable cause failure. We assume that the sequence of the q; 's is non-increasing. This means that changes made between stages of testing are not harmful to the system. The probability of success or the reliability in the i-th stage is, of course,  $r_i = 1 - q_0 - q_i$ . By "reliability growth" we mean that the r,'s increase from stage to stage. This is accomplished by a decrease in the  $q_i$ 's which must be brought about by appropriate engineering modifications of the system. We will obtain maximum likelihood estimates of  $q_0$ , and the  $q_i$ 's under the restriction that they are non-increasing, and a conservative lower confidence interval for  $\boldsymbol{r}_{\boldsymbol{k}},$  the reliability of the system in its final configuration of the test program.

<sup>\*</sup>Failures that reflect the state-of-the-art and whose elimination would require an advancement thereof.

Those which can be corrected by equipment or operational modifications.

It is worth remarking that the number of stages, K, and the number of trials,  $a_i + b_i + c_i$ , in the i-th stage may be fixed in advance or they may be random variables. Whichever the case, it will not alter the likelihood function corresponding to the experimental outcome on which our estimation procedure is based.

Let us compare our model with some of the others mentioned in the "Introduction." It shares with the work of Weiss, Madansky and Peisakoff, and Wolman the property that two types of failures (inherent and assignable cause) are distinguished.\* Unlike Wolman, we do not suppose in our model that the number of assignable cause failures is known in advance or that each has the same probability of causing a failure. Like Lloyd and Lipow (in their model leading to our Eq. (2)) and Madansky and Peisakoff, we consider that test data are batched according to stages of sampling of homogeneous test items. Unlike Lloyd and Lipow, (i.e., Eq. (2)) we do not impose an arbitrary growth pattern on our test results.

<sup>\*</sup>We will demonstrate the importance of this feature later by constructing a situation where, without this distinction, a nonsensical result obtains.

# III. THE LIKELIHOOD FUNCTION AND THE MAXIMUM LIKELIHOOD ESTIMATES

The likelihood function corresponding to  $a_i$  inherent failures,  $b_i$  assignable cause failures, and  $c_i$  successes in stage i, i = 1, ..., K is

(3) 
$$\frac{K}{\prod_{i=1}^{K}} \frac{(a_i + b_i + c_i)!}{a_i!b_i!c_i!} q_0^{a_i} q_i^{b_i} (1 - q_0 - q_i)^{c_i}.$$

Upon differentiating the log likelihood with respect to  $\mathbf{q}_{0}$  and  $\mathbf{q}_{1}$  and setting the derivatives equal to zero, we find for the maximum likelihood estimates

(4) 
$$\hat{q}_0 = \sum_{i=1}^{K} a_i / \sum_{i=1}^{K} (a_i + b_i + c_i)$$
,

and

(5) 
$$\hat{q}_i = (1 - \hat{q}_0) b_i / (b_i + c_i)$$
,  $i = 1,...,K$ .

Equations (5) are the maximum likelihood estimates of the  $q_i$ 's in general. We want to obtain maximum likelihood estimates of the  $q_i$ 's subject to the condition  $q_1 \ge q_2 \ge \dots \ge q_K$ . Adapting a result of Ayer, et al. [7] will give us these. Let  $\bar{q}_1$ ,  $\bar{q}_2$ ,...,  $\bar{q}_K$  denote the maximum likelihood estimates of  $q_1$ ,  $q_2$ ,...,  $q_K$  subject to the

<sup>\*</sup>This corresponds to our assumption that reliability does not decrease from stage to stage of testing.

condition  $q_1 \ge q_2 \ge \dots \ge q_K$ . If  $\hat{q}_1 \ge \hat{q}_2 \ge \dots \ge \hat{q}_K$ , then  $\bar{q}_i = \hat{q}_i$ ,  $i = 1, \dots, K$ . If  $\hat{q}_j < \hat{q}_{j+1}$  for some j  $(j=1, \dots, K-1)$ , then combine the observations in the j-th and (j+1)-st stages and compute the maximum likelihood estimates of the  $q_i$ 's by Eq. (5) for the K-1 stages thus formed. This procedure is continued until the estimates of the  $q_i$ 's form a non-increasing sequence. These estimates are the maximum likelihood estimates of the  $q_i$ 's subject to  $q_1 \ge q_2 \ge \dots \ge q_K$ . We will illustrate this procedure in Sec. IV, but first we will justify its validity.

Fix  $q_0$  and rewrite the likelihood Eq. (3) as

(6) 
$$L = \left[q_0^{\sum a_i} (1-q_0)^{\sum (b_i+c_i)} \prod \frac{(a_i+b_i+c_i)!}{a_i!b_i!c_i!}\right] \prod \left(q_i \over 1-q_0\right)^{b_i} \left(1 - \frac{q_i}{1-q_0}\right)^{c_i}.$$

Letting  $p_i = q_i / (1-q_o)$  so that  $p_1 \ge p_2 \ge \ldots \ge p_K$ , noting that  $p_i \in [0,1]$  since  $q_i \in [0,1-q_o]$ , and that the maximization of L with respect to the  $q_i$  does not involve the term in square brackets in Eq. (6), we find that we are in precisely the situation discussed by Ayer, et al. [7]. They find the maximum likelihood estimates for the  $p_i$ 's subject to the constraint  $p_1 \ge p_2 \ge \ldots \ge p_K$ . Thus, their maximum likelihood estimate of  $p_i$  is  $(1-q_o)$  times our maximum likelihood estimate of  $q_i$ . Maximizing on  $q_o$  we obtain the maximum likelihood estimate, Eq. (4), for  $q_o$  and are led to the maximum likelihood estimates for the  $q_i$ 's given in the preceding paragraph.

# IV. AN EXAMPLE

Suppose that a development testing program yielded the results shown in Table 1.

Table 1

Stage	Failures	Assignable Cause Failures b.	Successes	Trials	b <sub>i</sub>
	a i	i	c i	$a_i + b_i + c_i$	b <sub>i</sub> + c <sub>i</sub>
1 2 3 4 5 6 7 8 9	0 0 1 0 0 0 0	1 1 1 1 1 1 1 1	0 0 1 4 0 0 3 27	1 1 3 5 1 1 4 37	1 1 1 1/2 1/5 1 1 1/4 1/28
Totals	10	9	35	54	

Each stage of sampling, except the last, was terminated when an assignable cause failure occurred. A re-design effort was undertaken to eliminate the cause of failure, so that the test units in the succeeding stage were different from the earlier units but homogeneous in any given stage. We remark that this is the defining property of a stage, namely the homogeneity of all test units therein.

Note first that  $\hat{q}_0 = 10/54 = .1852$ . To construct the maximum likelihood estimates for the  $q_i$ 's subject to the condition that they be non-increasing, we must combine stages where there is a reversal

of non-increasingness of the ratios  $b_i/(b_i+c_i)$  until we get a non-increasing sequence.\* Table 2 indicates how this grouping is done.

Table 2

i	b <sub>i</sub>	c i	$\frac{b_{\mathbf{i}}}{(b_{\mathbf{i}} + c_{\mathbf{i}})}$	First Combination	Second Combination
1	1	0	1	1	1
2	1	0	1	1	1
3	1	0	1	1	1
4	1	1	1/2	1/2	1/2
5	1	4	1/5)	1/3)	
6	1	0	1 }	}	3/7
7	1	0	1 ′	1 )	
8	1	3	1/4	1/4	1/4
9	1	27	1/28	1/28	1/28

Observe that

$$\frac{b_5}{b_5 + c_5} < \frac{b_6}{b_6 + c_6} ,$$

so that we combined stages 5 and 6. There is yet a reversal between the ratios for the new fifth stage and the new sixth stage (the original seventh stage) so we next combine those stages. We now have eliminated all reversals and obtain as maximum likelihood estimates  $\bar{q}_i$  of the  $q_i$ 's subject to  $q_1 \geq q_2 \geq \ldots \geq q_K$ ,

<sup>\*</sup>It suffices to look at these ratios since the estimate of  $\hat{q}_{0}$  does not depend on the grouping of the data into stages.

$$\bar{q}_1 = \bar{q}_2 = \bar{q}_3 = 22/27 = .8148,$$
 $\bar{q}_4 = 11/27 = .4074,$ 
 $\bar{q}_5 = \bar{q}_6 = \bar{q}_7 = 22/63 = .3492,$ 
 $\bar{q}_8 = 11/54 = .2037,$  and
 $\bar{q}_9 = 11/378 = .0291.$ 

Thus the maximum likelihood estimate for  $r_9$ , the reliability of the system in its final test configuration, is

$$\bar{r}_9 = 1 - \hat{q}_0 - \bar{q}_9 = .7857$$
.

If no assumption of reliability growth were made -- that is, if all test units were (incorrectly) supposed to be homogeneous and if no distinction were made between inherent and assignable cause failures -- the estimate of reliability would be

$$\hat{r}_9 = \sum_i c_i / \sum_i (a_i + b_i + c_i) = 35/54 = .6481$$
.

# V. A CONSERVATIVE LOWER CONFIDENCE INTERVAL FOR SYSTEM RELIABILITY

In this section and the next we do not need the notion of a stage of testing, although we could, without violating our definition, consider each observation as a separate stage. Further, it is not necessary to distinguish between inherent and assignable cause failures.

We consider, as before, a model in which the reliability (probability of success) does not decrease from trial to trial; that is  $r_1 \le r_2 \le \ldots \le r_n$ . We seek a  $100(1-\alpha)$  per cent conservative lower confidence interval on  $r_n$ , the reliability of the system at the n-th trial. To this end, we cite a theorem of W. Hoeffding [8].

THEOREM: If X denotes the number of successes in n independent trials where the i-th trial has probability  $r_i$  of success,  $E[X] = \sum_{i=1}^{n} r_i = n\bar{r}$ , and c is an integer, then

(i) 
$$0 \le P[X \le c] \le \sum_{k=0}^{c} {n \choose k} (\bar{r})^k (1-\bar{r})^{n-k}$$
 if  $0 \le c \le n\bar{r}-1$ ,

(ii) 
$$0 < 1 - Q(n-c-1, 1-\bar{r}) \le P(X \le c) \le Q(c,\bar{r}) < 1$$
  
if  $n\bar{r}-1 < c < n\bar{r}$ ,

(iii) 
$$\sum_{k=0}^{c} \binom{n}{k} \left(\overline{r}\right)^k \left(1-\overline{r}\right)^{n-k} \leq P(X \leq c) \leq 1 \quad \text{if } n\overline{r} \leq c \leq n \text{ ,}$$

where

$$Q(c,\bar{r}) = \max_{0 \le S \le c} \sum_{k=0}^{c-S} {n-S \choose k} a^k (1-a)^{n-S-k},$$

$$a = (n\bar{r}-S)/(n-S).$$

<sup>\*</sup>A  $100(1-\alpha)$  per cent <u>conservative</u> (<u>exact</u>) lower confidence interval  $(a(\underline{X}), \infty)$  for a parameter  $\theta$ , given the sample information  $\underline{X}$ , is such that  $P[\theta > a(\underline{X})] \ge (=) 1-\alpha$ .

All bounds are attained. The upper bound for  $0 \le c \le n\bar{r}-1$  and the lower bound for  $n\bar{r} \le c < n$  are attained only if  $r_1 = r_2 = \dots = r_n = \bar{r}$ .

Denote the lower bound given by the theorem by  $b(c;\bar{r})$ . Observe that in each interval for c,  $b(c;\bar{r})$  is non-increasing in  $\bar{r}$  and non-decreasing in c.

Since we seek a  $100(1-\alpha)$  per cent conservative lower confidence interval, we set  $b(c;\bar{r}) = 1-\alpha$  (except in case (i) where this is impossible). This determines a function,  $c(\bar{r})$ , satisfying

(7) 
$$b(c(\bar{r}); \bar{r}) = 1 - \alpha$$
.

Having observed X successes, and setting X =  $c(\bar{r})$ , we solve Eq. (7) obtaining  $\bar{r} = \bar{r}_0$  as solution.

Now note that the following events are equivalent:

(a) 
$$X \leq c(\bar{r})$$
,

(b) 
$$X = c(\bar{r}_0) \le c(\bar{r})$$
,

(c) 
$$\bar{r} \geq \bar{r}_0$$
.

Events (a) and (b) are the same by definition of  $c(\bar{r}_0)$ , and events (b) and (c) are equivalent by the observation following the statement of Hoeffding's theorem. Thus,

$$P[\bar{r} \geq \bar{r} | \bar{r}] = P[X \leq c(\bar{r}) | \bar{r}] \geq b(c; \bar{r}) = 1 - \alpha.$$

Since  $r_1 \le \dots \le r_n$ ,  $r_n \ge \bar{r}$ , and thus  $P[r_n \ge \bar{r}_0 | \bar{r}] \ge 1 - \alpha$ .

In using bound (ii) or (iii), one must compare  $n\bar{r}_0$  with c, the observed number of successes.

We remark finally that the above discussion is a modification of the classical theory of confidence bounds discussed by Lehmann [9, pp. 78-80].

Example: In the development testing program cited in Sec. IV, 35 successes were recorded in 54 trials. Using binomial tables, we find that  $.54 < \bar{r}_0 < .55$  at the 95 per cent confidence level. (Bound (iii) is in order here since  $c = 35 \ge n\bar{r}_0 \ge 54(.54) = 29.16$ .) Hence we are 95 per cent confident that  $r_{54} \ge .54$ . However, it is a conservative confidence statement as we noted earlier. It is, in fact the same estimate we could obtain assuming no reliability growth; i.e.,  $r_1 = r_2 = \dots = r_n$ .

Note that if one looks at only the results of stage 9, standard methods yield for 27 successes in 37 trials a lower 95 per cent confidence limit for the reliability in stage 9 of .58. This merely shows that if enough data are available from the last stage, the standard binomial approach may be preferred. Our method, however, enables one to use the data from <u>all</u> stages.

# VI. MINIMUM NUMBER OF TESTS TO ACHIEVE SPECIFIED RELIABILITY

As another application of Hoeffding's bounds, we can determine the minimum number of tests necessary to establish a specified reliability r, assuming that the critical number c of successes and the probability of a type I error,  $\alpha$ , are fixed in advance.

Consider the problem of testing  $H_0$ :  $\bar{r} \geq r^*$  versus  $H_1$ :  $\bar{r} < r^*$ . Note that  $\bar{r} \geq r^*$  implies  $r_n \geq r^*$  under the assumption  $r_1 \leq r_2 \leq \ldots \leq r_n$ , but not conversely. The usual binomial test is to accept  $H_0$  if the number of successes, X, exceeds c-1 and to reject otherwise. Now by (i) of the Hoeffding bounds cited in Sec. V,

$$P[reject H_{o}|H_{o}] = P[X < c | r_{1} \le ... \le r_{n}; \bar{r} = r^{*}]$$

$$\le \sum_{k=0}^{c-1} \binom{n}{k} (r^{*})^{k} (1-r^{*})^{n-k} \quad \text{if } c \le nr^{*}.$$

Hence, if we determine n such that

$$\sum_{k=0}^{c-1} \binom{n}{k} (r^*)^k (1-r^*)^{n-k} = \alpha ,$$

and n >  $c/r^*$ , we will protect the probability of a type I error under H . The minimum n satisfying these conditions will determine the length of the test program.

Example: If  $\alpha = .05$ , c = 20,  $r^* = .8$ , so that  $c/r^* = 25$ , we find that n = 29 suffices since

$$\sum_{k=0}^{19} {28 \choose k} (.8)^k (.2)^{28-k} = .090 ,$$

while

$$\sum_{k=0}^{19} \binom{29}{k} (.8)^k (.2)^{29-k} = .049.$$

# VIII. A TREND TEST FOR RELIABILITY GROWTH

In the foregoing we have assumed that the probability of an assignable cause failure does not increase during the development testing program. We feel that the validity of this hypothesis would be determined on the basis of engineering knowledge. However, we propose a test for reliability growth; that is, for non-increasingness of the  $\mathbf{q_i}$ 's.

Mann [10] has given two tests against downward trend and provided tables for their use. Specifically, we are given data  $X_1, X_2, \ldots, X_n$  in that order. The null hypothesis is that the X's are randomly arranged. The alternative hypothesis is that  $X_i$  has continuous cumulative distribution function  $F_i$ , with  $F_i(t) < F_{i+k}(t)$  for every i, every t, and every k > 0; that is, the sequence of the  $X_i$ 's is stochastically decreasing. To test against upward trend, merely test  $-X_1, -X_2, \ldots, -X_n$  against downward trend.

Suppose each stage of testing is terminated when an assignable cause failure occurs. We identify  $X_i$  with the number of trials since the last assignable cause failure. The  $X_i$ 's should increase if reliability growth is taking place. Note, however, that here we are dealing with a discrete random variable so that the c.d.f. will not be continuous. We can circumvent this problem by adding a uniform [0,1] random variable to each of the random variables suggested above without changing the appropriate probabilities under the null hypothesis. We can then apply one of the Mann procedures to this new random variable.

# VII. BINOMIAL VS. TRINOMIAL MODELS

In this section we construct an example to show that it would not suffice to consider a binomial model for reliability growth using the maximum likelihood approach of Sec. III. We do this by exhibiting an experimental outcome in which the maximum likelihood estimate for r under a binomial model is nonsensical while the corresponding estimate under our trinomial model is eminently reasonable.

Suppose we consider a binomial model in which we make no distinction between inherent and assignable cause failures. Denote the probability of success at trial i by  $\mathbf{r_i}$  and assume as before that  $\mathbf{r_1} \leq \mathbf{r_2} \leq \ldots \leq \mathbf{r_n}$ . The unrestricted maximum likelihood estimate of  $\mathbf{r_i}$  is 0 or 1, according as failure or success is observed at trial i. To obtain the maximum likelihood estimates of the  $\mathbf{r_i}$ 's under the restriction  $\mathbf{r_1} \leq \mathbf{r_2} \leq \ldots \leq \mathbf{r_n}$ , one invokes the procedures of Ayer, et al. [7], which we used in Sec. III. However, if the n-th trial results in a success, the maximum likelihood estimate of  $\mathbf{r_n}$  will be unity -- independent of what transpired on earlier trials. In particular, this would be the maximum likelihood estimate of  $\mathbf{r_n}$  even if all trials prior to the n-th had been failures. On the other hand, if the n-th trial were a success, our trinomial model would give as the maximum likelihood estimate for  $\mathbf{r_n}$  the proportion of successes observed in the n trials.

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